

Notice of References Cited

Application/Control No.

09/675,427

Applicant(s)/Patent Under
Reexamination
SAXENA ET AL.

Examiner

Morella I Rosales-Hanner

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,356,861	03-2002	Singhal et al.	703/2
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zanella, S.;Nardi, A.;Quarantelli, M.; Neviani, A; Guardiani, C., "Analysis of the impact of intra-die variance on clock skew", 12 June 1999, Statistical Metrology. IWSM. 1999 4th International Workshop on. Pages 14 -17
	V	Guardiani, C.; Nicollini, G.; Franzini, B.; Design for manufacturability: a two-step analytic modeling approach;Circuits and Systems, 1992. ISCAS '92. Proceedings., 1992 IEEE International Symposium on , Volume: 4 , 3-6 May 1992 Pages:1997 - 2000 vol.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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